Errata

X-Ray Powder Diffraction Data of a New Compound

Na₂Ca₄Mg₂Si₄O₁₅

By Robert Hausner
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The following entries, omitted in the original publication of
the above article, should be entered in Table 2.

1.919  74  620,713  47.341
1.987  2  622  47.919

In the data entry, Table 2, beginning 1.634 the bar above
the 114 entry was incorrectly positioned. It should 114.

Powder Diffraction Data for Nitroguanidine, C(NH₂)₂NNO₂

By E.K. Vasil’ev, A.N. Sapochnivov, Z.A. Dobronravova and
L.I. Vereshchagin
The Institute of the Earth’s Crust, Academy of Sciences, Siberian De-
partment, Irkutsk 664033, U.S.S.R.

The entire concluding paragraph, part of which was missing
in the original publication of this article, and the reference
listings, also missing, are given below:

Compared to PDF 7-634, which was obtained by camera
methods, the data in Table 2 are of higher precision and
accuracy (from the use of an internal standard) in interpla-
nar spacings, cover a wider range and contain additional
weak and moderate intensity reflections.

References
9, 573-578.
234-239.
47, 1063.

Dr. William M. Fink
We regret to announce the death of William M. Fink, one of the founders of the International Centre for
Diffraction Data. Dr. Fink died April 2, 1992, at the age of 95.

International Report

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Results of Election of Officers and Directors
JCPDS—International Centre for Diffraction Data
March 1992
Chairman – Gerald G. Johnson, Jr.
Vice Chairman – Jan W. Visser
Treasurer – Gerhard R. Fischer
Chairman, Technical Committee — Ting C. Huang
Members-at-Large, Board of Directors
Thomas N. Blanton
Walter Eysel
James A. Kaduk
Melvin H. Meuller
Robert L. Snyder
Past Chairman – Ludo K. Frevel

Daniel Louër to Receive the J.D. Hanawalt Award
The JCPDS—International Centre for Diffraction Data
takes pleasure in announcing that Professor Daniel Louër,
Université de Rennes I, Rennes, France, has been selected
to receive the J.D. Hanawalt Award for excellence in the
field of powder diffraction. The presentation of the award
will take place at the European Powder Diffraction
Conference, EPDIC-2, Enschede, The Netherlands, July-

Calendar of Meetings

1992

ICDD Clinic on X-Ray Powder Diffraction
June 1992 Fundamentals
June 1992 Advanced Techniques
Swarthmore College, Swarthmore, Pennsylvania, USA.
The ICDD X-Ray Clinics are the continuation of the SUNY
Clinics which, for some twenty-five years, were held at the
State University of New York at Albany. The ICDD assumed
responsibility for these clinics in 1990. The Clinic is presented
in two separate week-long sessions, each of which stands
alone as a complete course.

Contact: Mario Fornoff, ICDD X-Ray Clinic, International
Centre for Diffraction Data, 1601 Park Lane, Swarth-
more, PA 19081, USA. Phone (215) 329-9400, FAX (215)
328-2503

Symposium Roentgendiffraktometrie in der
Materialwissenschaft
June 25-26, 1992
Freiberg/Sachsen, Germany
Contact: Simone Neubert, Freiberger Praziisionsmechanik
GmbH, Hainichener Strasse 2 a, D-9200 Freiberg, Germany.

ICDD Clinic on X-Ray Fluorescence Spectroscopy
July 1992 Fundamentals
July 1992 Advanced Techniques
Swarthmore College, Swarthmore, Pennsylvania, USA
Details and Contact: Same as ICDD Clinic on X-Ray Powder
Diffraction (above).

Second European Powder Diffraction Conference
(EPDiC2)
July 30-August 1, 1992
University of Twente, The Netherlands
Contact: Chairman Scientific Program: Prof. Dr. E. Tillmans,
Institute fur Mineralogie und Kristallographie der Universitat
Wien, or Chairman Organizing Committee: Dr. T. W. Ryan,
Philips Analytical, Lelyweg 1, 7602 EA Almelo, The Nether-
lands, phone +31 5490 39443.

This meeting, intended as a forum for all European pow-
der diffractionists, is scheduled to be held at the University
of Twente, between Hengelo and Enschede, in the beautiful
eastern part of the Netherlands, preceding the 14th Euro-
pean Crystallographic Meeting (ECM-14), August 3-7, 1992,
at the same location. All practical and theoretical aspects of
powder diffraction are welcome. The subjects of Glass and
amorphous substances, Electron diffraction, Thin films, Syn-
chrotron radiation, Stress analysis, and Structure determina-
tion from powder data will be highlighted.

14th European Crystallographic Meeting (ECM-14)
August 2-7, 1992
Enschede, The Netherlands
Contact: ECM-14, Dr. H.J. Bruins Slot, Secretary, CAOS/
CAMM Center, University of Nijmegen, Toernooiveld, 6525
ED Nijmegen, The Netherlands

1992 Annual Denver Conference on Applications
of X-Ray Analysis
August 3-7, 1992
Colorado Springs, Colorado, USA
Contact: Lynne Bonno, Conference Secretary, Department
of Engineering, University of Denver, Denver, CO 80208,
USA. Phone (303) 871-3515.

Special sessions include the Plenary Session on Grazing
Incidence X-ray Characterization of Materials, Low Atomic
Number XRF (Be-F) and Chemical State Analysis, On-Line
Application of X-ray Analysis, Applications of XRF to Indus-
trial Processes, Imaging/ Tomography, Applications of Total
Diffraction Patterns, High Temperature Non-ambient X-ray
Diffraction, Polymer Diffraction, and X-ray Stress Analysis.
Tutorial Workshops (1/2 day unless otherwise noted) sched-
uled are Calibration and Maintenance of X-ray Spectrome-
ters; XRF Sample Preparation (one day); Use of Pure Intensi-
fies for XRF Math Corrections; X-ray Microbeam Imaging
and Analysis; Alignment and Calibration of Diffractometers;
XRD Sample Preparation and Presentation (Including Films); Production of High Quality Experimental and Reduced Powder Patterns; Polymer Diffraction, SAXS; X-ray Characterization of Thin Films (one day); High Temperature XRD; and Use of Parallel-beam Optics for XRD.

XVth Conference on Applied Crystallography
August 9-12, 1992
Cieszyn, Poland
The conference is organized by the Institute of Physics and Chemistry of Metals at the Silesian University in Katowice jointly with the Institute of Ferrous Metallurgy in Gliwice and with the support of the Crystallography Committee of the Polish Academy of Sciences. The scientific program includes the following topics: (1) real structure of materials (metals, ceramics, polymers, etc.), and (2) research methods and equipment (phase identification, precision measurement of lattice constants, determination of crystallite sizes and distortions, texture, high temperature X-ray techniques, small-angle scattering, X-ray topography, etc.)

American Crystallographic Association 1992 Meeting
August 9-14, 1992
Pittsburgh, Pennsylvania, USA
Contact: Marcia J. Vair, ACA, PO Box 96, Ellicott Station, Buffalo, NY 14205-0096, USA.

Rietveld Summer School
August 13-15, 1992
Cieszyn, Poland
The school is organized by the Commission on Powder Diffraction, IUCr, Silesian University (Katowice, Poland), and the Institute of Ferrous Metallurgy (Gliwice, Poland) with the financial support of the International Union of Crystallography and will be held just after the closing of the XVth Conference on Applied Crystallography. The school will consist of lectures and practical training.

Issues and Controversy: The Measurement of Crystalline Silica
August 20-21, 1992
Boston, Massachusetts, USA
The meeting is sponsored by the Chemical Manufacturers Association/CHEMSTAR Crystalline Silica Panel.

International Seminar on Structural Investigations at Pulsed Neutron Sources
September 1-4, 1992
Dubna, Moscow region, Russia
Two sections are scheduled: TOF-Diffractionmetry (performing an experiment on a high resolution diffractometer, developing the Fourier diffracometry technique, time resolved experiments, transition processes, real crystal structures) and Small Angle Neutron Scattering.

Contact: Dr. Yu. V. Taran, Laboratory of Neutron Physics of the Joint Institute for Nuclear Research, 141980 Dubna, Moscow region, Russia.

International Centre for Diffraction Data
Fall Technical Meetings
October 21-22, 1992
Concordville, Pennsylvania, USA
Contact: Ms. Josephine Felizzi, JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, PA 19081, USA. Phone (215) 328-9403.

First Crystallography Conference of the Asian Crystallographic Association
November 13-16, 1992
Singapore
Contact: Conference Organization: Professor N. Kasai, Applied Chemistry, Osaka University, 2-1 Yamadoka Suite, Osaka 565, Japan. Scientific Programme: Dr. E. N. Maslen, Crystallographic Centre, University Centre, University of Western Australia, Nedlands 6009, WA, Australia.

Materials Research Society Fall Meeting
November 30-December 4, 1992
Boston, Massachusetts, USA
Contact: M. Geil, Materials Research Society, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373.

1993

International Centre for Diffraction Data
Spring Technical Meetings and Annual Meeting
March 17-18, 1993
Concordville, Pennsylvania, USA
Contact: Ms. Josephine Felizzi, JCPDS-International Centre for Diffraction Data, 1601 Park Lane, Swarthmore, PA 19081, USA. Phone (215) 328-9403.

British Crystallographic Association Spring Meeting
March 29-April 2, 1993
Manchester, England
Contact: Dr. B. Beagley, Department of Chemistry, UMIST, PO Box 88, Manchester M60 1QD, England

Materials Research Society
May 17-22, 1993
Anaheim, California, USA
Contact: M. Geil, Materials Research Society, 9800 McKnight Road, Suite 327, Pittsburgh, PA 15237, USA. Phone (412) 367-3003; FAX (412) 367-4373
Meeting Reports

The 1991 Fall Meeting of the Materials Research Society
Boston, Massachusetts, USA
December 2-6, 1991
Reported by Winnie Wong-Ng, National Institute of Standards and Technology

Following the past tradition, the 1991 Materials Research Society (MRS) Fall Meeting again took place at the Copley Square Compound of Boston. Nearly 4000 attendees gathered at the Marriott and the Westin Hotels for a five-day intensive meeting. A comprehensive program was coordinated by nearly 100 symposium organizers. Because of the multidisciplinary nature of the MRS, the program covered a wide spectrum of materials research and featured some 2700 technical papers. It was an informative and exciting meeting.

A total of 26 symposia were offered on topics ranging from traditional basic science to new frontiers and nonconventional topics: materials preparation and modification, theory and design, processing, thin films and interfaces, electronic materials, high temperature superconductors, optical materials and organic materials.

Three major poster sessions were held in the evenings. These were popular sessions for attendees to discuss scientific research on the forefront, exchange ideas and meet new people. Snacks and beverages were also served during these gatherings which made them even more attractive. These sessions often finished late at night.

The special events of the meetings included the Plenary presentation on “U. S. Science Policy for the 1990s” given by Dr. A. Bromley, Assistant to the President for Science and Technology; the presentation of the Von Hippel Award to T.H. Geballe of Stanford University, and the presentations of the MRS Medal to S. Somiya and B.S. Meyerson. The late news session highlighted the recent observations of visible luminescence at room temperature from highly porous Si.

The MRS comprehensive short course program was held in parallel with the MRS meeting at the same location. A total of 21 courses designed for continuing education and featuring the latest developments in material science were offered. These courses often complemented the symposium topics. They included specialty courses with in-depth instruction and survey courses on fundamental topics in the areas covering advanced materials, preparation, fabrication, characterization and techniques.

This meeting also featured a large scale analytical and processing equipment exhibit which also complemented the technical symposia. Among the approximately 130 representatives were ICDD and several X-ray diffraction equipment manufacturers. The MRS book exhibit this year featured a sale of past symposia proceedings which attracted quite a few buyers.

This successful meeting concluded on Friday afternoon amidst a holiday atmosphere and a dusting of snow.